

Search Notes

Application/Control No.

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Examiner

TAN X. DINH

Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
369	13.12 13.11	2/27/2007	T.D
369	13.13	2/27/2007	T.D
369	13.2	2/27/2007	T.D
369	13.21	2/27/2007	T.D

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	2/27/2007	T.D